EIN PRESSWIRE

Flynn Systems Adds New onTAP JTAG Controller to Meet Intel’s Core i7™ and Atom™ Microarchitecture Requirements

onTAP’s new JTAG Controller offers expanded test coverage to include Intel’s Core i7 and ultra-low voltage Atom processors

NASHUA , NEW HAMPSHIRE, UNITED STATES, June 23, 2016 /EINPresswire.com/ -- Flynn Systems has developed a new boundary scan JTAG Controller that now gives users the ability to incorporate expanded test coverage to include the Intel® Core™ i7 and Intel Atom microarchitecture, usingonTAP® Boundary Scan test software.

Hank Flynn, President of Flynn Systems, stated that “Low voltage, low power technology is key to successful consumer devices. Our improved TAP CONNECT JTAG Controller provides a means to test these low voltage and ultra-low voltage processors. Our Controller provides dual ports, each up to 30MHz, that adjust to target board voltages and includes an internal voltage source. Controller pins may be used for JTAG or GPIO and multiple TAP CONNECT JTAG Controllers may be used per application.”

> “
>
> Low voltage-low power technology is key to successful consumer devices.
>
> *Hank Flynn, President Flynn Systems Corp.*

The 1.05V TAP voltages, 50 Ohm pull-up and pull-down resistors and common TDI and TDO pin connections for multiple chains, all found in Intel’s i7 and Atom applications, are supported in the new Controller.

Along with Core™ i7 configurations, onTAP and the TAP CONNECT JTAG Controller provide many additional boundary scan test benefits.
- Automatic, netlist-based, test generation
- Test coverage and precision diagnostics for IEEE 1149.1 and 1149.6 AC specifications
- Precision diagnostics for infrastructure and interconnect faults
- Cluster test coverage for non-JTAG parts such as DDR memory and I2C bus devices
- Flash programming
- In-system programming
- Support for multiple TAPs and JTAG chains
- ProScan test vector visualizer and analyzer tool
- BSDL syntax and semantics check

Driven by customer feedback, the development of the new TAP CONNECT JTAG Controller is part of Flynn Systems’ commitment to deliver the latest product updates. The Boundary Scan JTAG Controller is available by contacting Flynn Systems via email to sales@flynn.com or visiting www.flynn.com.

Founded in 1986, Flynn Systems is a worldwide leader in boundary scan test software. The company offers a wide range of Boundary Scan products and services designed to provide test and development engineers alike with the tools for excellence in circuit board designs and testing.

Wendy Harrison
Flynn Systems Corp.
6035984444
email us here
